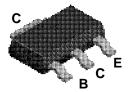


# Discrete Power & Signal Technologies

**July 1998** 

# **FZT649**



**SOT-223** 

# **NPN Low Saturation Transistor**

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

# **Absolute Maximum Ratings\*** T<sub>A = 25°C unless otherwise noted</sub>

Symbol	Parameter	FZT649	Units
V <sub>CEO</sub>	Collector-Emitter Voltage	25	V
V <sub>CBO</sub>	Collector-Base Voltage	35	V
V <sub>EBO</sub>	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	А
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range	-55 to +150	°C

<sup>\*</sup>These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

## NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

# Thermal Characteristics $T_{A=25^{\circ}\text{C unless otherwise noted}}$

Symbol	Characteristic	Max	Units
		FZT649	
P <sub>D</sub>	Total Device Dissipation	2	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	°C/W

# **NPN Low Saturation Transistor**

(continued)

## **Electrical Characteristics**

 $T_{\text{A}\,=\,25^{\circ}\text{C}\,\text{unless otherwise noted}}$ 

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	RACTERISTICS				
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	I <sub>C</sub> = 10 mA	25		V
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	I <sub>C</sub> = 100 μA	35		V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	I <sub>E</sub> = 100 μA	5		V
I <sub>CBO</sub>	Collector Cutoff Current	V <sub>CB</sub> = 30 V		100	nA
		$V_{CB} = 30 \text{ V}, T_A = 100^{\circ}\text{C}$		10	uA
I <sub>EBO</sub>	Emitter Cutoff Current	V <sub>EB</sub> = 4V		100	nA
ON CHAF	ACTERISTICS*				
h <sub>FE</sub>	DC Current Gain	$I_C = 50 \text{ mA}, V_{CE} = 2 \text{ V}$	70		-
		I <sub>C</sub> = 1 A, V <sub>CE</sub> = 2 V	100	300	
		$I_C = 2 A$ , $V_{CE} = 2 V$	75		
		I <sub>C</sub> = 6 A, V <sub>CE</sub> = 2 V	15		
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	I <sub>C</sub> = 1 A, I <sub>B</sub> = 100 mA		300	mV
()		I <sub>C</sub> = 3 A, I <sub>B</sub> = 300 mA		600	
V <sub>BE(sat)</sub>	Base-Emitter Saturation Voltage	I <sub>C</sub> = 1 A, I <sub>B</sub> = 100 mA		1.25	V
V <sub>BE(on)</sub>	Base-Emitter On Voltage	I <sub>C</sub> = 1 A, V <sub>CE</sub> = 2 V		1	V
SMALL S	IGNAL CHARACTERISTICS				
C <sub>obo</sub>	Output Capacitance	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1MHz		50	pF
f <sub>T</sub>	Transition Frequency	I <sub>C</sub> = 100 mA,V <sub>CE</sub> = 5 V, f=100MHz	150		-

\*Pulse Test: Pulse Width  $\leq 300~\mu s,~Duty~Cycle \leq 2.0\%$ 

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